

Project No: TM-2509000453P
Report No.: TMWK2509004188KS

FCC ID: 2BAFJ-TCTR03

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SAR TEST REPORT

FCC 47 CFR § 2.1093

for

LCD DISPLAY

Model No.: TPC-TR03

Prepared for:

LABAU Technology Corp

9F No 531-1 Zhongzheng Rd., Xindian Dist, New Taipei City, 23148 Taiwan

Prepared by

Compliance Certification Services Inc.

Wugu Lab.

No.11, Wugong 6th Rd., Wugu Dist.,
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Issue Date: February 5, 2026

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Revision History

Rev.	Issue Date	Revisions	Effect Page	Revised By
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1 Attestation of Test Results

Applicant Name	LABAU Technology Corp
Model Name	TPC-TR03
Applicable Standards	FCC 47 CFR § 2.1093 Published RF exposure KDB procedures
Receive EUT Date:	September 30, 2025
Date Tested	December 29, 2025
Test Results	Exempt
Compliance Certification Services Inc. , tested the above equipment in accordance with the requirements set forth in the above standards. Determination of compliance is based on the results of the compliance measurement,not taking into account measurement instrumentation uncertainty.All indications of Pass/Fail in this report are opinions expressed by Compliance Certification Services Inc, based on interpretations and/or observations of test results. The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report.	
Approved & Released By: 	Tested by: 
Sky Zhou Asst. Section Manager Compliance Certification Services Inc.	KW Huang Engineer Compliance Certification Services Inc.



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2 Test Specification, Methods and Procedures

The tests documented in this report were performed in accordance with FCC 47 CFR § 2.1093 and the following FCC Published RF exposure [KDB](#) procedures:

- 447498 D01 General RF Exposure Guidance v06
- 865664 D02 RF Exposure Reporting v01r02



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3 Device Under Test (DUT) Information

3.1 DUT Description

Applicant Name	LABAU Technology Corp
Applicant Address	9F No 531-1 Zhongzheng Rd., Xindian Dist, New Taipei City, 23148 Taiwan
Manufacturer Name	HP Inc.
Manufacturer Address	1501 Page Mill Road,Palo Alto,CA94304,USA
Product	LCD DISPLAY
Trade Name	HP
Model No.	TPC-TR03
Model Discrepancy	N/A
HW Version	V25014B-1
SW Version	V2510310
Sample Stage	PVT
SKU	SKU 1: Display+Camera+No Touch SKU 2: Display+Camera+Touch SKU 3: Display+Camera+Touch+NFC SKU 4: Display+Camera+Touch+NFC+Scanner

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3.2 Wireless Technologies

Wireless technologies	Frequency bands	Operating mode
NFC	13.56 MHz	ASK
Antenna Specification	Type	Loop Antenna

Notes:

1. The sample selected for test was prototype that representative to production product and was provided by manufacturer
2. Variant information between/among model numbers / trademarks is provided by the applicant, test results of this report are applicable to the sample EUT received of main test model name.
3. Antenna information is provided by the applicant, test results of this report are applicable to the sample EUT received.
4. SAR test exemption.

4 RF Exposure Conditions

Evaluated with a minimum test separation distance of 5 mm.

4.1 Standalone SAR Test Exclusion Considerations

Since the Dedicated Host Approach is applied, the standalone SAR test exclusion procedure specified in KDB 447498 is applied.

SAR Test Exclusion Calculations

NFC

4.3.1 b) 1.

{[Power allowed at numeric threshold for 50 mm in step a)] + [(test separation distance – 50 mm)·(f(MHz)/150)]} mW, for 100 MHz to 1500 MHz

f(GHz)	0.1
min. test separation distance (mm)	5
Threshold at 50 mm	474
b) 1. SAR test exclusion thresholds (mW)	444

4.3.1 C) 1.

the power threshold at the corresponding test separation distance at 100 MHz in step b) is multiplied by $[1 + \log(100/f(\text{MHz}))]$

f(GHz)	0.01356
b) 1. SAR test exclusion thresholds (mW)	444
c) 1. SAR test exclusion thresholds (mW)	830

4.3.1 C) 2.

For test separation distances ≤ 50 mm, the power threshold determined by the equation in c) 1) for 50 mm and 100 MHz is multiplied by $\frac{1}{2}$

4.3.1 C) 2.	
f(GHz)	0.01356
max. Electric field strength (dBuV/m @3m)	80.6
max. EIRP power (dBm)	-14.63
max. EIRP Tune up power (dBm)	-14
max. EIRP power (mW)	0
min. test separation distance (mm)	5
c) 1. SAR test exclusion thresholds (mW)	830
c) 2. SAR test exclusion thresholds (mW)	415
Result	Pass

Note(s):

- Maximum Electric Field Strength Reference Test Report TMWK2509004187KR.



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5 Facilities

All measurement facilities used to collect the measurement data are located at

☒ No.11, Wugong 6th Rd., Wugu Dist., New Taipei City 24891, Taiwan.

END OF REPORT